

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/069,912 | Applicant(s)/Patent Under Reexamination UEDA ET AL. | |
| | Examiner Cam N Nguyen | Art Unit 1754 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| | A | US-3,923,696 | 12-1975 | Chart et al. | 502/307 |
| | B | US-4,673,663 | 06-1987 | Magnier, Claude | 502/320 |
| | C | US-5,851,948 | 12-1998 | Chuang et al. | 502/314 |
| | D | US-3,920,583 | 11-1975 | Pugh, Stanley Frederick | 502/314 |
| | E | US-4,515,905 | 05-1985 | Uytterhoeven et al. | 502/309 |
| | F | US-4,752,599 | 06-1988 | Nakamura et al. | 502/257 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.